

**Notice of References Cited**Application/Control No.  
10/088,114Applicant(s)/Patent Under  
Reexamination  
INOUE ET AL.Examiner  
John F. Belena, Ph.D.Art Unit  
3746

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,660,045	08-1997	Ito et al.	60/737
	B	US-4,898,001	02-1990	Kuroda et al.	60/733
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08135969 A	05-1996	Japan	YOSHIDA et al.	F23R 03/26
	O	JP 55046309 A	04-1980	Japan	KUSABA et al.	F23R 03/28
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

V